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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Walter SCHWARZENBACH et al. Confirmation No.: 3337  
Application No.: 10/766,207 Group Art Unit: 2822  
Filing Date: January 29, 2004 Examiner: Khanh B. Duong  
For: METHOD FOR DETACHING A LAYER FROM A WAFER USING A LOCALIZED STARTING AREA Attorney Docket No.: 4717-11600

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450  
Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a PTO form 1449 which lists twenty-seven (27) references for the Examiner's review and consideration. These references were cited in related applications and copies of non-US references are enclosed. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

The fee which is believed to be due for the filing of this statement is \$180. Please charge all required fees to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

Date: \_\_\_\_\_

11/29/05


Allan A. Fanucci (Reg. No. 30,256)

**WINSTON & STRAWN LLP**  
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12/02/2005 HDEMESS1 00000002 501814 10766207

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 <p style="text-align: center;"><b>LIST OF REFERENCES CITED BY APPLICANT</b>  <b>Form PTO-1449</b>  <i>(Use several sheets if necessary)</i></p> <p style="text-align: center;">Sheet 1 of 2</p>	<b>ATTY. DOCKET NO.:</b> <b>4717-11600</b>	<b>APPLICATION NO.:</b> <b>10/766,207</b>
	<b>APPLICANT:</b> <b>Walter SCHWARZENBACH et al.</b>	
	<b>FILING DATE:</b> <b>January 29, 2004</b>	<b>GROUP:</b>

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	CITE NO.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,374,564	12/1994	Bruel	437	24	
	AB	6,013,563	1/2000	Henley et al.	438	458	
	AC	6,048,411	4/2000	Henley et al.	148	33.5	
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	AE	6,150,239	11/2000	Goesele et al.	438	458	
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	AG	6,391,799 B1	5/2002	Di Cioccio	438	781	
	AH	6,413,874 B1	7/2002	Sato	438	714	
	AI	6,830,631 B2	12/2004	Nenyei et al.	134	37	
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	AL	2002/0056519	5/2002	Henley et al.	156	344	
	AM	2002/0115264	8/2002	Henley et al.	438	458	

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AN	EP 1 256 973 B1	12/2004	Europe			X	
	AO	EP 1 258 909 A2	11/2002	Europe			X	
	AP	EP 0 533 551 B1	8/2000	Europe			X	
	AQ	EP 0 948 032 A2	10/1999	Europe			X	
	AR	EP 0 926 713 A2	6/1999	Europe			X	
	AS	EP 0 961 312 A2	12/1999	Europe			X	
	AT	EP 1 045 448 A1	10/2000	Europe			X	
	AU	EP 1 100 127 A1	5/2001	Europe			X	
	AV	EP 0 291 147	11/1988	Europe			X	
	A W	DE 100 08 829 B4 w/ English Abstract	9/2001	Germany			X	
	AX	WO 99/49501	9/1999	PCT			X	
	AY	WO 01/63002 A1	8/2001	pct			X	
	AZ	WO 02/37556 A1	5/2002	PCT			X	

<b>OTHER REFERENCES</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>		
	BA	Chin Teng Lin et al., "Temperature Control Of Rapid Thermal Processing System Using Adaptive Fuzzy Network", Fuzzy Sets and Systems, Vol. 103, pp. 49-65 (1999)
<b>EXAMINER</b>		<b>DATE CONSIDERED</b>
<p><b>*EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with <b>MPEP 609</b>. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>		